

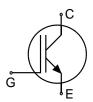
## **IGBT3 Power Chip**

#### Features:

- 1700V Trench & Field Stop technology
- low turn-off losses
- short tail current
- positive temperature coefficient
- easy paralleling

### This chip is used for:

- power modules
- **Applications:**
- drives



Chip Type	V <sub>CE</sub>	I <sub>C</sub>	Die Size	Package
SIGC101T170R3E	1700V	75A	10.03 x 10.03 mm <sup>2</sup>	sawn on foil

### **Mechanical Parameters**

Raster size	10.03 x 10.03		
Emitter pad size (incl. gate pad)	8 x ( 3.82 x 1.75 )		
Gate pad size	1.309 x 0.844	mm <sup>2</sup>	
Area total	100.6		
Thickness	190	μm	
Wafer size	200	mm	
Max.possible chips per wafer	258		
Passivation frontside	Photoimide		
Pad metal	3200 nm AlSiCu		
Backside metal	Ni Ag –system suitable for epoxy and soft solder die bonding		
Die bond	Electrically conductive glue or solder		
Wire bond	Al, <500µm		
Reject ink dot size	Ø 0.65mm ; max 1.2mm		
Recommended storage environment	Store in original container, in dry nitrogen, in dark environment, < 6 month at an ambient temperature of 23°C		



### **Maximum Ratings**

Parameter	Symbol	Value	Unit	
Collector-Emitter voltage, <i>T</i> <sub>vj</sub> =25 °C	V <sub>CE</sub>	1700	V	
DC collector current, limited by $T_{vj max}$	I <sub>C</sub>	1)	Α	
Pulsed collector current, $t_p$ limited by $T_{vj max}$	I <sub>c,puls</sub>	225	А	
Gate emitter voltage	V <sub>GE</sub>	±20	V	
Junction temperature range	T <sub>vj</sub>	-40 +175	°C	
Operating junction temperature	T <sub>vj</sub>	-40+150	°C	
Short circuit data <sup>2)</sup> $V_{GE}$ = 15V, $V_{CC}$ = 1000V, $T_{vj}$ = 150°C	t <sub>SC</sub>	10	μs	
Reverse bias safe operating area <sup>2)</sup> (RBSOA)	$I_{C,max} = 150A, V_{CE,max} = 1700V$ $T_{vj} \le 150^{\circ}C$			

<sup>1)</sup> depending on thermal properties of assembly

<sup>2)</sup> not subject to production test - verified by design/characterization

# Static Characteristic (tested on wafer), $\mathcal{T}_{vj}$ =25 $^{\circ}\text{C}$

Parameter	Symbol	Conditions	Value			Unit
T arameter	Cymbol	Conditions	min.	typ.	max.	
Collector-Emitter breakdown voltage	V <sub>(BR)CES</sub>	<i>V</i> <sub>GE</sub> =0V , <i>I</i> <sub>C</sub> = 3 mA	1700			
Collector-Emitter saturation voltage	V <sub>CEsat</sub>	V <sub>GE</sub> =15V, <i>I</i> <sub>C</sub> =75A	1.6	2	2.4	V
Gate-Emitter threshold voltage	V <sub>GE(th)</sub>	$I_{\rm C}$ =3mA , $V_{\rm GE}$ = $V_{\rm CE}$	5.2	5.8	6.4	
Zero gate voltage collector current	I <sub>CES</sub>	V <sub>CE</sub> =1700V , V <sub>GE</sub> =0V			4.33	μA
Gate-Emitter leakage current	I <sub>GES</sub>	<i>V</i> <sub>CE</sub> =0V , <i>V</i> <sub>GE</sub> =20V			600	nA
Integrated gate resistor	r <sub>G</sub>			8.5		Ω

## **Dynamic Characteristic** (not subject to production test - verified by design / characterization), $T_{vj}$ =25 °C

Parameter	Symbol	Conditions	Value			l Imit
Falameter	Symbol		min.	typ.	max.	Unit
Input capacitance	Cies	$V_{CE}=25V,$		6638		~ -
Reverse transfer capacitance	C <sub>res</sub>	V <sub>GE</sub> =0V, <i>f</i> =1MHz		220		- pF

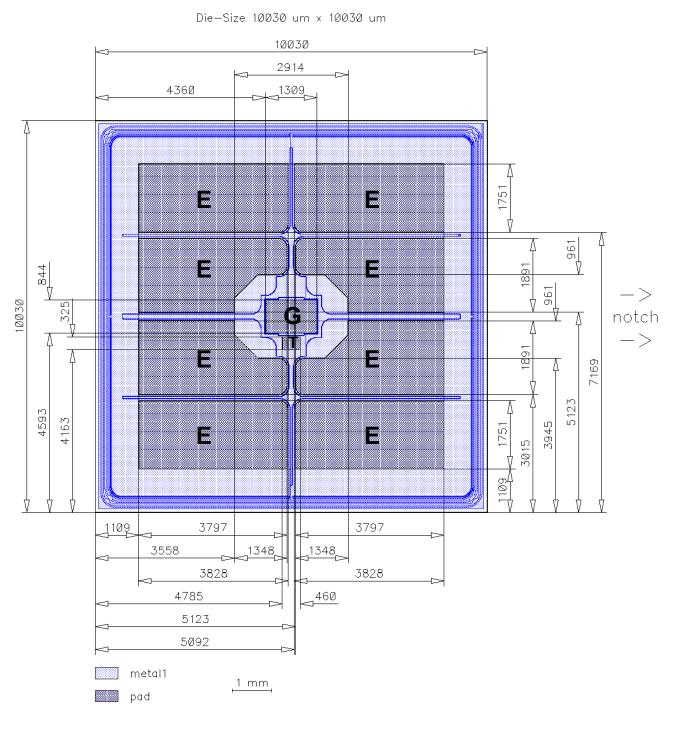


### **Further Electrical Characteristic**

Switching characteristics and thermal properties are depending strongly on module design and mounting technology and can therefore not be specified for a bare die.



## **Chip Drawing**



- E = Emitter
- $\mathbf{G} = \text{Gate}$
- T = Test pad do not contact



#### Description

AQL 0,65 for visual inspection according to failure catalogue

Electrostatic Discharge Sensitive Device according to MIL-STD 883

### **Revision History**

Version	sion Subjects (major changes since last revision)	
2.1	Change wafer size to 200 mm	14.04.2010
2.2	Additional basic type L7777M, L7777T, L7777E; new gate pad design	01.07.2014

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